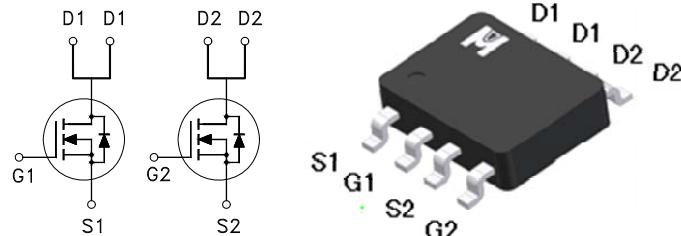


Dual N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV_{DSS}	30V
$R_{DS(on)}$ (MAX.)	21mΩ
I_D	7.5A



UIS, R_g 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_A = 25^\circ C$	I_D	7.5	A
	$T_A = 100^\circ C$		5.5	
Pulsed Drain Current ¹		I_{DM}	30	
Avalanche Current		I_{AS}	10	
Avalanche Energy	$L = 0.1mH, I_D=7.5A, R_G=25\Omega$	E_{AS}	2.8	mJ
Repetitive Avalanche Energy ²	$L = 0.05mH$	E_{AR}	1.4	
Power Dissipation	$T_A = 25^\circ C$	P_D	2	W
	$T_A = 100^\circ C$		0.8	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	°C

100% UIS testing in condition of $V_D=15V$, $L=0.1mH$, $V_G=10V$, $I_L=7.5A$, Rated $V_{DS}=30V$ N-CH

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$	25	62.5	°C / W
Junction-to-Ambient ³	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.

²Duty cycle ≤ 1%

³62.5°C / W when mounted on a 1 in² pad of 2 oz copper.

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.5	3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 24V, V_{GS} = 0V$			1	μA
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 10V, V_{GS} = 10V$	7.5			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 10V, I_D = 7.5\text{A}$		18	21	$\text{m}\Omega$
		$V_{GS} = 4.5V, I_D = 5.5\text{A}$		34	42	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 7.5\text{A}$		16		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1\text{MHz}$		520		pF
Output Capacitance	C_{oss}			88		
Reverse Transfer Capacitance	C_{rss}			62		
Gate Resistance	R_g	$V_{GS} = 15\text{mV}, V_{DS} = 0V, f = 1\text{MHz}$		2.0		Ω
Total Gate Charge ^{1,2}	$Q_g(V_{GS}=10V)$	$V_{DS} = 15V, V_{GS} = 10V, I_D = 7.5\text{A}$		11.5		nC
	$Q_g(V_{GS}=5V)$			5		
Gate-Source Charge ^{1,2}	Q_{gs}			1.6		
Gate-Drain Charge ^{1,2}	Q_{gd}			2.8		
Turn-On Delay Time ^{1,2}	$t_{d(on)}$	$V_{DS} = 15V, I_D = 1\text{A}, V_{GS} = 10V, R_{GS} = 6\Omega$		9		nS
Rise Time ^{1,2}	t_r			12		
Turn-Off Delay Time ^{1,2}	$t_{d(off)}$			30		
Fall Time ^{1,2}	t_f			15		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_S	$I_F = I_S, V_{GS} = 0V$			2.3	A
Pulsed Current ³	I_{SM}				9.2	
Forward Voltage ¹	V_{SD}				1.2	
Reverse Recovery Time	t_{rr}			50		
Peak Reverse Recovery Current	$I_{RM(\text{REC})}$			30		
Reverse Recovery Charge	Q_{rr}			2		

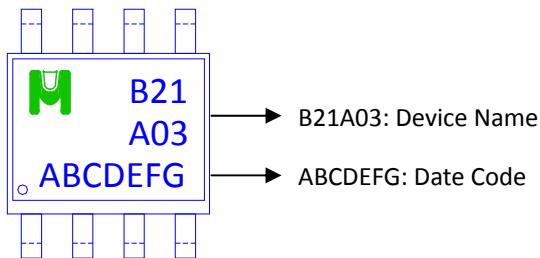
¹Pulse test : Pulse Width \leq 300 μ sec, Duty Cycle \leq 2%.

²Independent of operating temperature.

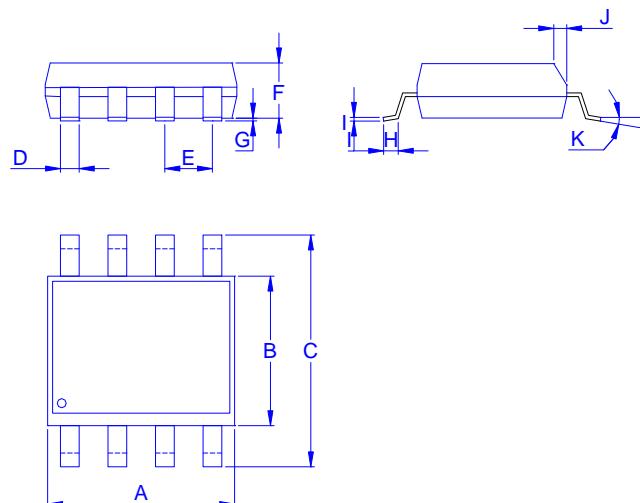
³Pulse width limited by maximum junction temperature.

Ordering & Marking Information:

Device Name: EMB21A03G for SOP-8



Outline Drawing



Dimension in mm

Dimension	A	B	C	D	E	F	G	H	I	J	K
in.	4.70	3.70	5.80	0.33		1.20	0.08	0.40	0.19	0.25	0°
Typ.					1.27						
Max.	5.10	4.10	6.20	0.51		1.62	0.28	0.83	0.26	0.50	8°

